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Integrated circuits - Measurement of electromagnetic immunity -
Part 8: Measurement of radiated immunity - IC stripline method

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CONTENTS

INTERNATIONAL ELECTROTECHNICAL COMMISSION

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This redline version of the official IEC Standard allows the user to identify the changes made to the previous edition IEC 62132-8:2012. A vertical bar appears in the margin wherever a change has been made. Additions are in green text, deletions are in strikethrough red text.

IEC 62132-8 has been prepared by subcommittee 47A: Integrated circuits, of IEC technical committee 47: Semiconductor devices. It is an International Standard.

This second edition cancels and replaces the first edition published in 2012. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

a) frequency range of 150 kHz to 3 GHz was deleted from the scope;
b) extension of upper usable frequency to 6 GHz or higher as long as the defined requirements are fulfilled.

The text of this Internation Standard is based on the following documents:

FDIS	Report on voting
47A/1205/FDIS	47A/1209/RVD

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

This part of IEC 62132 is to be read in conjunction with IEC 62132-1.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at www.iec.ch/members_experts/refdocs. The main document types developed by IEC are described in greater detail at www.iec.ch/publications.

A list of all the parts in the IEC 62132 series, published under the general title *Integrated circuits - Measurement of electromagnetic immunity*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

– reconfirmed,
– withdrawn, or
– revised.

1 Scope

This part of IEC 62132 specifies a method for measuring the immunity of an integrated circuit (IC) to radio frequency (RF) radiated electromagnetic disturbances ~~over the frequency range of 150 kHz to 3 GHz~~ using an IC stripline.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

~~IEC 60050 (all parts), *International Electrotechnical Vocabulary* (available at http://www.electropedia.org)~~

IEC 60050-131, *International Electrotechnical Vocabulary (IEV) - Part 131: Circuit theory*

IEC 60050-161, *International Electrotechnical Vocabulary (IEV) - Part 161: Electromagnetic compatibility*

~~IEC 61000-4-20, *Electromagnetic compatibility (EMC) – Part 4-20: Testing and measurement techniques – Emission and immunity testing in transverse electromagnetic (TEM) waveguides*~~

IEC 62132-1~~:2006~~, *Integrated circuits - Measurement of electromagnetic immunity~~, 150 kHz to 1 GHz~~ - Part 1: General conditions and definitions*

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~~[1] KÖRBER, KLOTZ, MUELLER, TREBECK. *IC- Stripline – A new Proposal for Susceptibility and Emission Testing of ICs, EMC COMPO 2007*~~

~~[2] KÖRBER, MUELLER, TREBECK. *IC- Streifenleitung – Neues Messverfahren zur Bewertung der EMV- Eigenschaften von Halbleitern* (only available in German)*, EMV Düsseldorf 2008*~~

[1] SCHNEIDER M. V.. Microstrip Lines for Microwave Integrated Circuits. The Bell System Technical Journal, May 1969, vol. 48, pp. 1421–1444,

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[3] Ledong Chen , Jianfei Wu, Yifei Zheng, Hongyi Wang and Liming Zheng. A Novel IC-Stripline Cell Design Based on Image Theory, Electronics 2022, 11

[4] IEC 61000-4-20, *Electromagnetic compatibility (EMC) - Part 4-20: Testing and measurement techniques - Emission and immunity testing in transverse electromagnetic (TEM) waveguides*

[5] UNGER H.-G.. Elektromagnetische Theorie für Hochfrequenztechnik, Teil 1: Allgemeine Gesetze und Verfahren, Antennen und Funkübertragung, planare, rechteckige und zylindrische Wellenleiter, (only available in German) Hüthig Verlag 1988.

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